

<b>Notice of References Cited</b>		Application/Control No. 10/522,720	Applicant(s)/Patent Under Reexamination KAWAKAMI, TAKASHI	
		Examiner HENOK G. HEYI	Art Unit 2627	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,226,672 B1	05-2001	DeMartin et al.	709/219
*	B	US-6,542,445 B2	04-2003	Ijichi et al.	369/30.08
*	C	US-2003/0167318 A1	09-2003	Robbin et al.	709/221
*	D	US-2004/0213552 A1	10-2004	Kato, Motoki	386/069
*	E	US-2004/0252604 A1	12-2004	Johnson et al.	369/047.22
*	F	US-2005/0273632 A1	12-2005	Kawakami, Takashi	713/193
*	G	US-7,130,251 B1	10-2006	Morohashi, Akihiro	369/47.13
*	H	US-7,237,198 B1	06-2007	Chaney, Jeremy P.	715/730
I	US-				
J	US-				
K	US-				
L	US-				
M	US-				

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2003029795 A	01-2003	Japan	SAWAI, MASAHIRO	G10L 19/00
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.